

s4.m14.o4 **TEM Investigation of Aerinite, Compared with Synchrotron and X-Ray Powder Diffraction Data.**

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Aerinite $(\text{Ca}_{5.1}\text{Na}_{0.5})(\text{Fe}^{3+}\text{AlFe}^{2+}_{1.7}\text{Mg}_{0.3})(\text{Al}_{5.1}\text{Mg}_{0.7})[\text{Si}_{12}\text{O}_{36}(\text{OH})_{12}\text{H}][(\text{CO}_3)_{1.2}(\text{H}_2\text{O})_{12}]$, a blue fibrous silicate mineral associated with the alteration of ophiitic rocks in the southern Pyrenees, occurs in the Camporells – Estopanyà area (Huesca – Lleida, Spain) and was commonly used as a blue pigment in most Catalan roman paintings between the XI – XV centuries. Its crystal structure was studied by TEM at 300 kV with a FEI Tecnai F30 ST. Unit cell parameters ($a = b = 16.8820(9)$, $c = 5.2251(3)$ Å, $\alpha = \beta = 90^\circ$, $\gamma = 120^\circ$) have been obtained through tilt series using a double tilt–rotation holder in nano diffraction mode [1] and confirm the values derived from powder diffraction by Rius et al. [2]. Tilts were performed from the initial zone [100] around axis b^* : [101], [10 $\bar{1}$], [10 $\bar{2}$], [201], [20 $\bar{1}$], [203], [20 $\bar{3}$], [301], [302], [304], [403]. The zone axes [210], [310], [3 $\bar{1}$ 0], [320], [410], [4 $\bar{1}$ 0], [430], [520], [5 $\bar{2}$ 0], [530], [540], [750] have been registered from an initial zone [100] around axis c^* . HREM images were obtained in the following crystallographic orientations: [001], [101], [110], [$\bar{1}$ 11], [102], [120], [201], [122], [203], [301], [1 $\bar{1}$ 9], [1 $\bar{2}$ 4] but still four space groups were left over. Recently Rius et al. [3] have determined its crystal structure in space group $P3c1$ by applying the direct methods modulus sum function to synchrotron and X-ray powder diffraction data. Using the structure model of Rius et al. [3] and the program CERIOUS 4.2 [4] the kinematically calculated electron diffraction patterns and the simulated HREM images gave a good agreement with experimental TEM data.

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s4.m14.o5 **Structural investigations of nanocrystalline TiO₂ samples.** I. Djerdj, A. M. Tonejc and A. Tonejc, University of Zagreb, Faculty of Science, Dept. of Physics, Bijenicka 32, P.O.Box 331, 10002 Zagreb, Croatia. E-mail: idjerdj@phy.hr

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TiO₂ is used in many applications such as photovoltaic devices, integrated wave guides, gas and humidity sensors, inorganic membranes, catalyst supports and electrochemical displays [1, 2]. Two kinds of nanocrystalline TiO₂ samples were synthesized by the sol-gel method: iron doped TiO₂ (containing iron as a solid solution and poly(ethylene)glycol) and undoped TiO₂. The former sample exhibits the anatase modification, while the latter also contains, besides anatase (74 %), a small amount of brookite (26 %). Samples were characterized by means of X-ray diffraction (XRD) at room temperature using a Philips powder diffractometer (PW 1820) with monochromatized $\text{CuK}\alpha$ radiation. Transmission electron microscopy (TEM) investigations were carried out by using a JEOL JEM 2010 200 kV microscope, (Cs=0.5 mm, point resolution 0.19 nm) with a beryllium window energy-dispersive (EDS) detector. The Rietveld refinement of X-ray diffraction (XRD, $R_{\text{wp}}=10$ %) and selected area electron diffraction (SAED, $R_{\text{wp}}=15$ %) methods were used in order to extract structural parameters of TiO₂ using the FULLPROF program [3]. The crystal structure was refined in the space group of anatase $I4_1/amd$ (141) and in the space group of brookite $Pbca$ (61). The dependence of the lattice parameters of anatase on the grain size and average microstrain were determined. The lattice parameter a increased while the parameter c decreased with decreasing of the grain size, while the unit cell volume was almost constant. The Debye-Waller parameters B for our samples were enhanced in comparison with previous results obtained from neutron diffraction on coarse-grained TiO₂ powders (anatase) [4]. Significant differences of lattice parameters, bond lengths and angles were found between undoped and iron doped samples. The size-strain analysis was performed using the Rietveld method, and assuming that both size broadening and microstrain broadening are of Lorentzian profile type. The average microstrain decreased with the increase of the treatment temperature from 1.2 % for as prepared undoped sample to 0.67 % for annealed sample at 500°C.

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